

# CDE Res Map



## Facts

- The CDE Resmap 4 point resistivity mapper is used for measuring resistivity across the wafer for substrates and thin films.
- The system can do automated resistivity mapping for pieces to 8 inch wafers.

## Personnel

- Process Engineer - [Sean O'Brien](#)
- Process Engineer - [Patricia Meller](#)
- Equipment Engineer - [Peter Morici](#)

## Manuals & Users

- [CDE ResMap Manual](#)